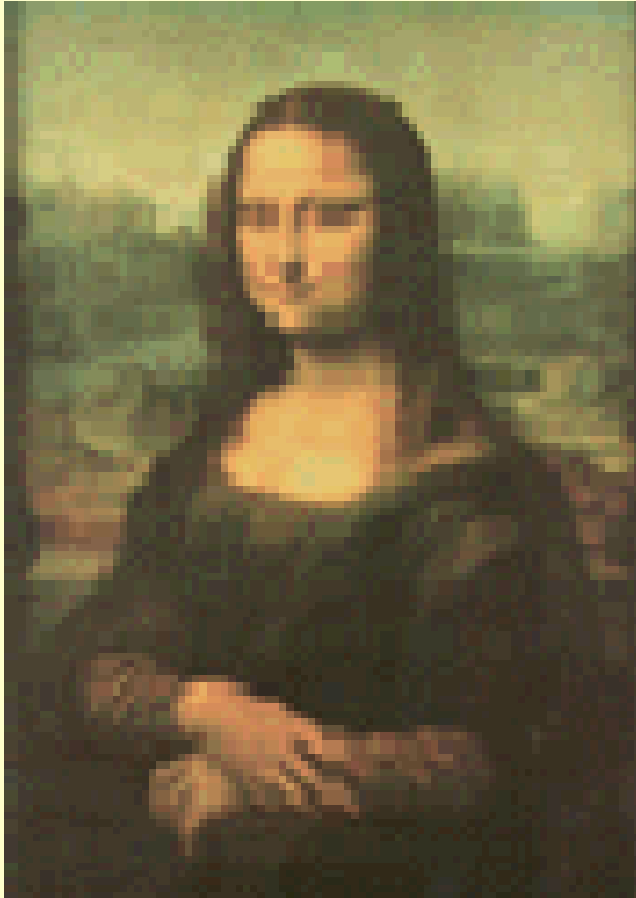
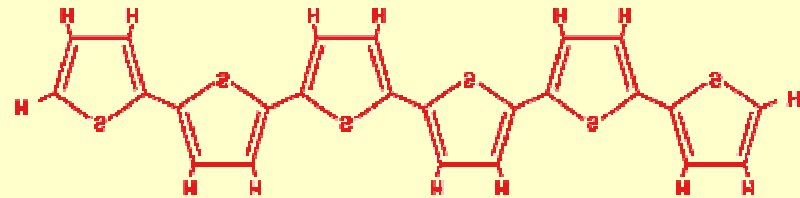


MONA-LISA



Electrical Measurements on FETs of T6

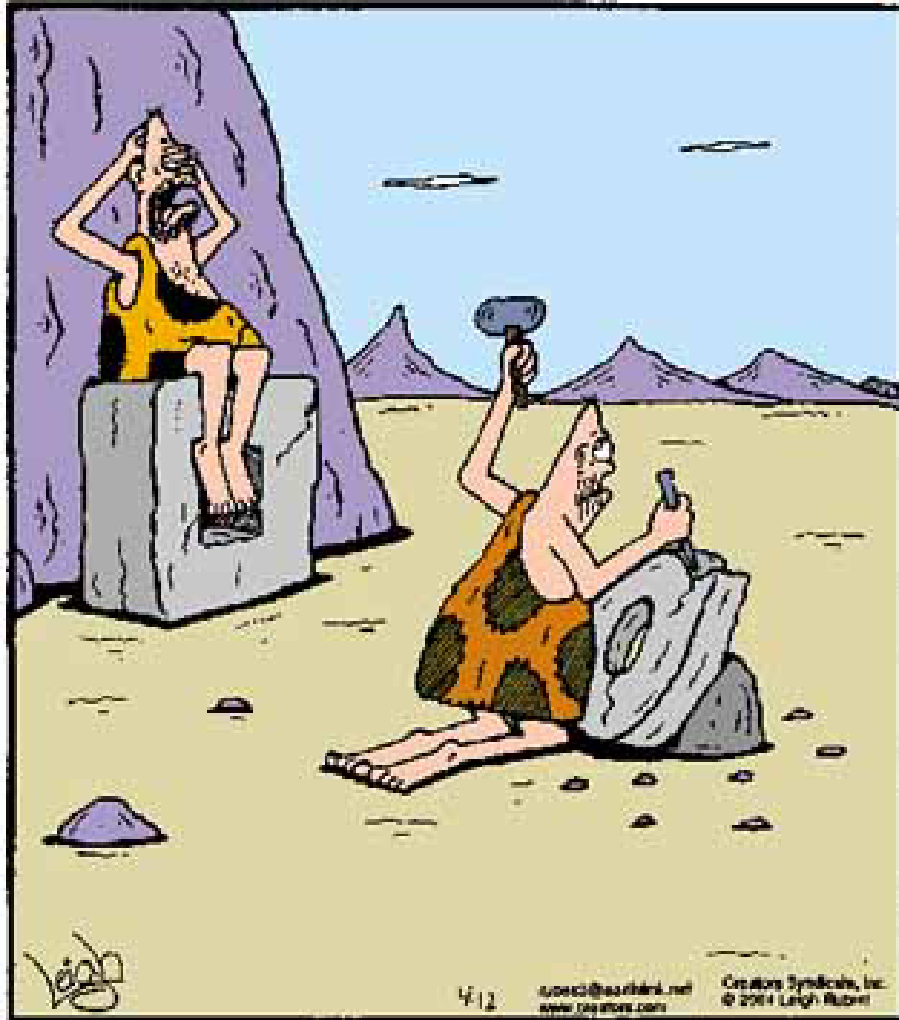


Faro, 29.06.2001

H.L. Gomes, P. Stallinga



Physics of FETs



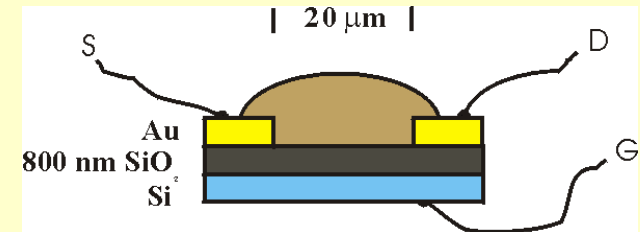
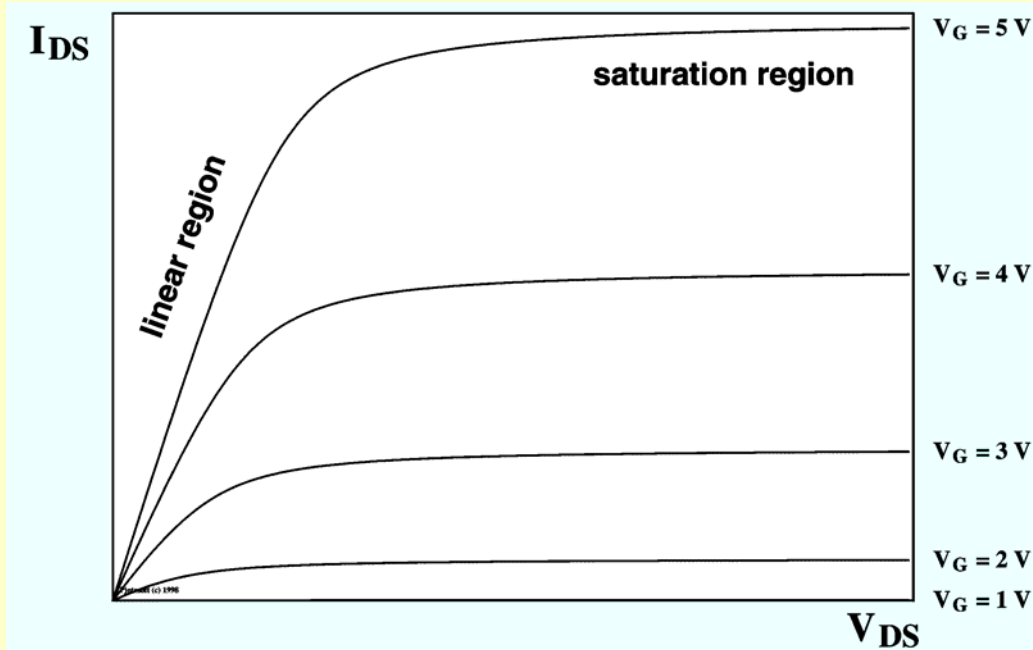
"I don't know why you're wasting your time. There's no point in reinventing the wheel."

Organic materials are like any other semiconductor

No point in reinventing the wheel



Physics of FETs

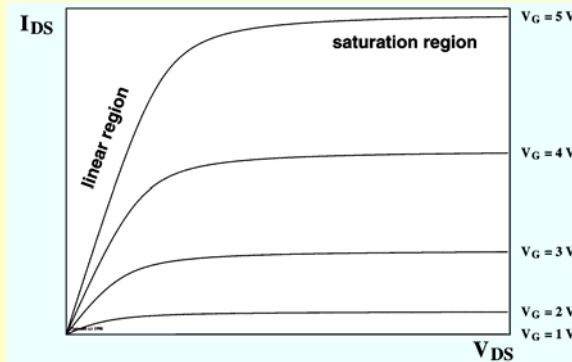


FET in linear region:
$$I_{DS} = \frac{Z}{L} \mu_p C_i (V_G - V_T) V_D$$

FET in saturation region:
$$I_{DS} = \frac{mZ}{L} \mu_p C_i (V_G - V_T)^2$$

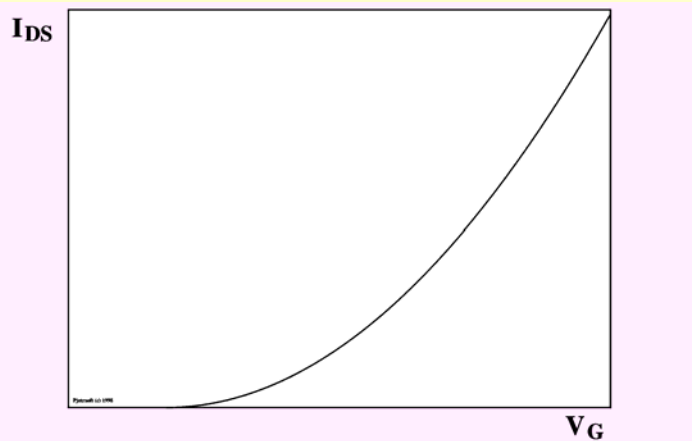


Standard FET curves; theory

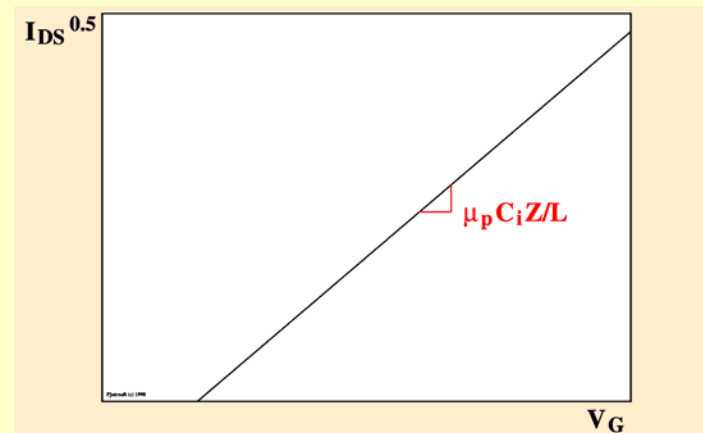


$$I_{DS} = \frac{mZ}{L} \mu_p C_i (V_G - V_T)^2$$

In saturation we can easily extract the mobility



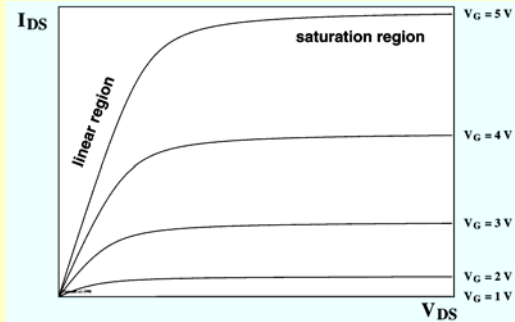
Linear plot



Square-root plot

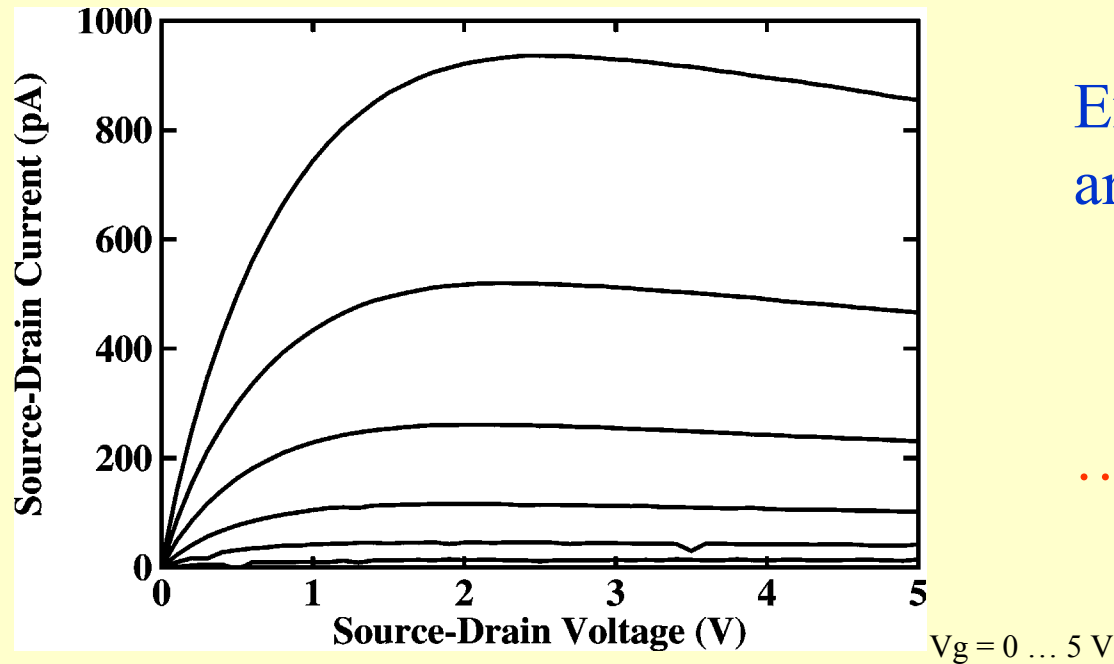


Experimental α T6 FET curves



theoretical

experimental

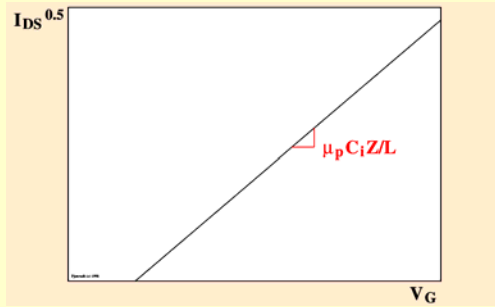


Experimental curves
are close to theoretical

..... but not quite!

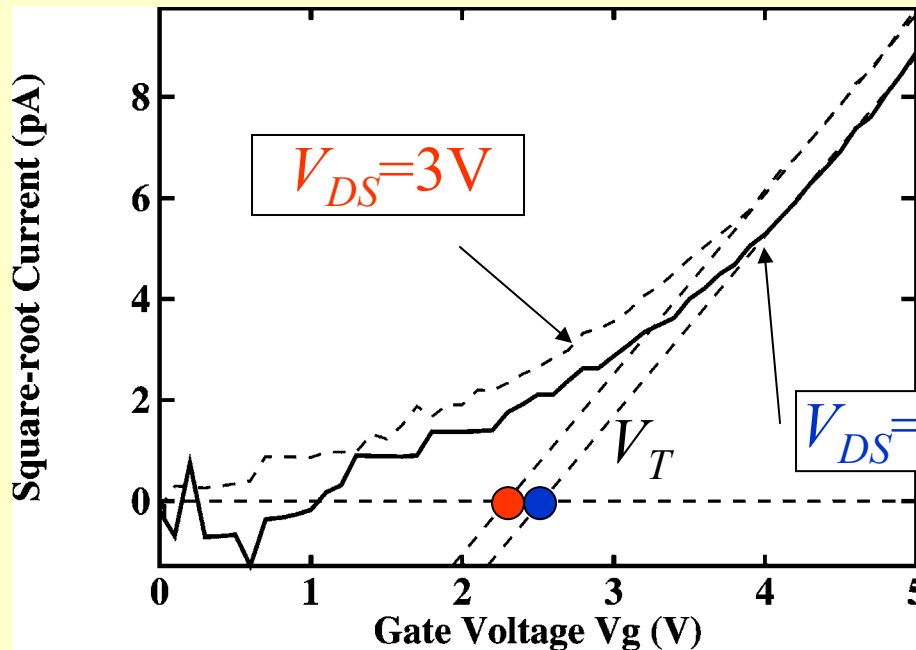


Experimental α T6 FET transfer curves



theoretical

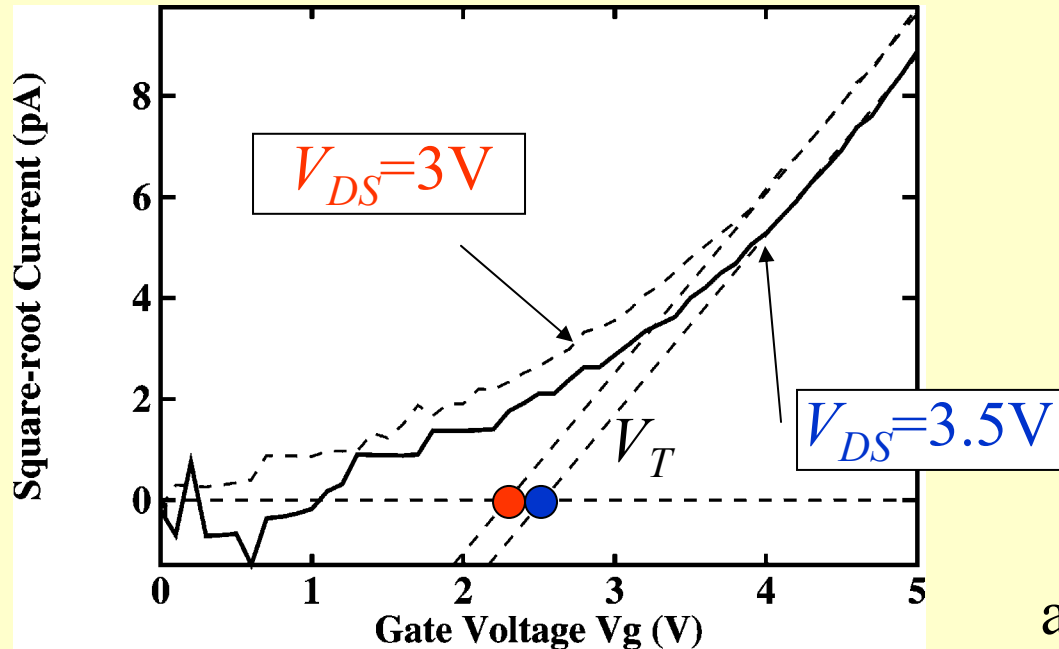
experimental



Dropping off of current for increasing V_{DS} is due to higher threshold voltage V_T



Experimental α T6 FET transfer curves



In saturation

V_T is V_{DS} dependent

“For high(er) dopings, V_T also becomes V_G -dependent”

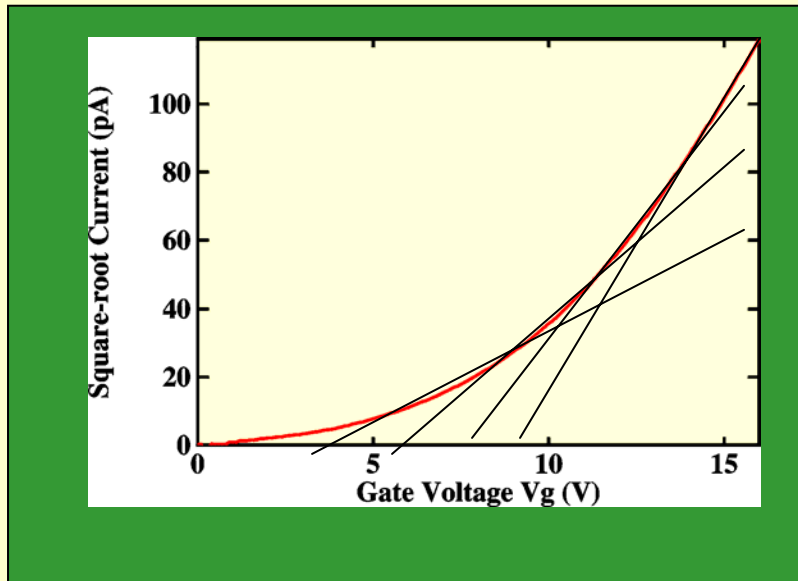
Sze, p. 442

$$V_T = \frac{1}{C_i} \sqrt{2\varepsilon_s q N_A (2\psi_B)} + 2\psi_B$$

For increased V_{DS} we have more free carriers N_A



Transverse Electric Field Dependence



Experimental:

Slope of transfer curve (mobility μ_p) depends on V_G (transverse electric field)

Higher field \rightarrow higher mobility

Literature:

Higher field \rightarrow lower mobility

Example (from Sze, p.449):

“At a given temperature, mobility decreases with increasing effective transverse field”

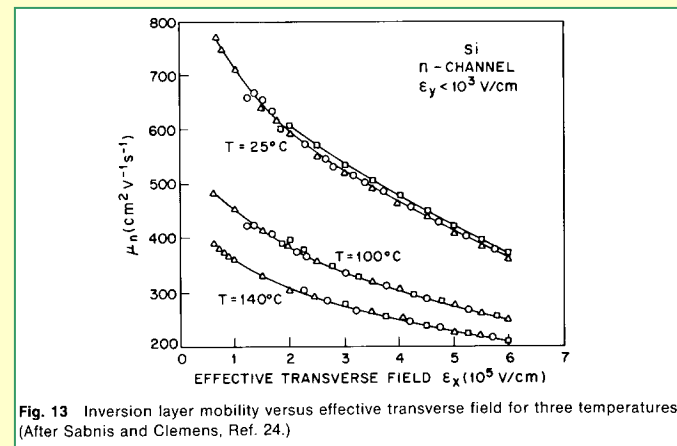
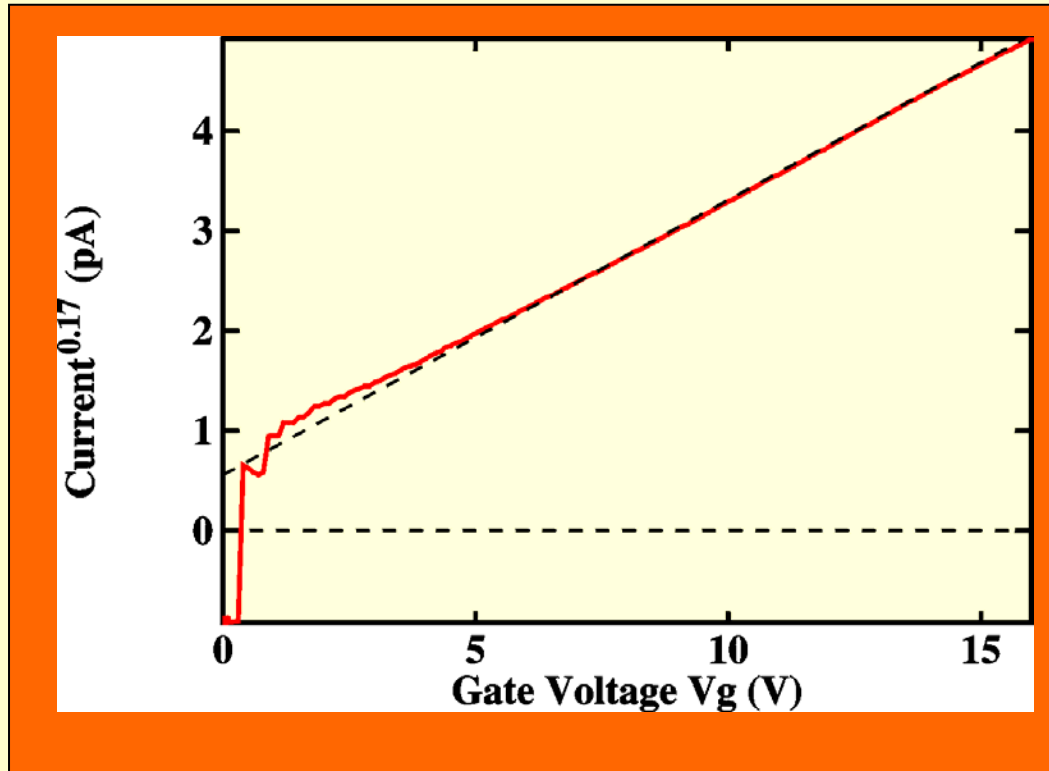


Fig. 13 Inversion layer mobility versus effective transverse field for three temperatures. (After Sabnis and Clemens, Ref. 24.)



6th Power law



Same data plotted as

$$\sqrt[6]{I_{DS}} \text{ vs } V_g$$

gives straight line

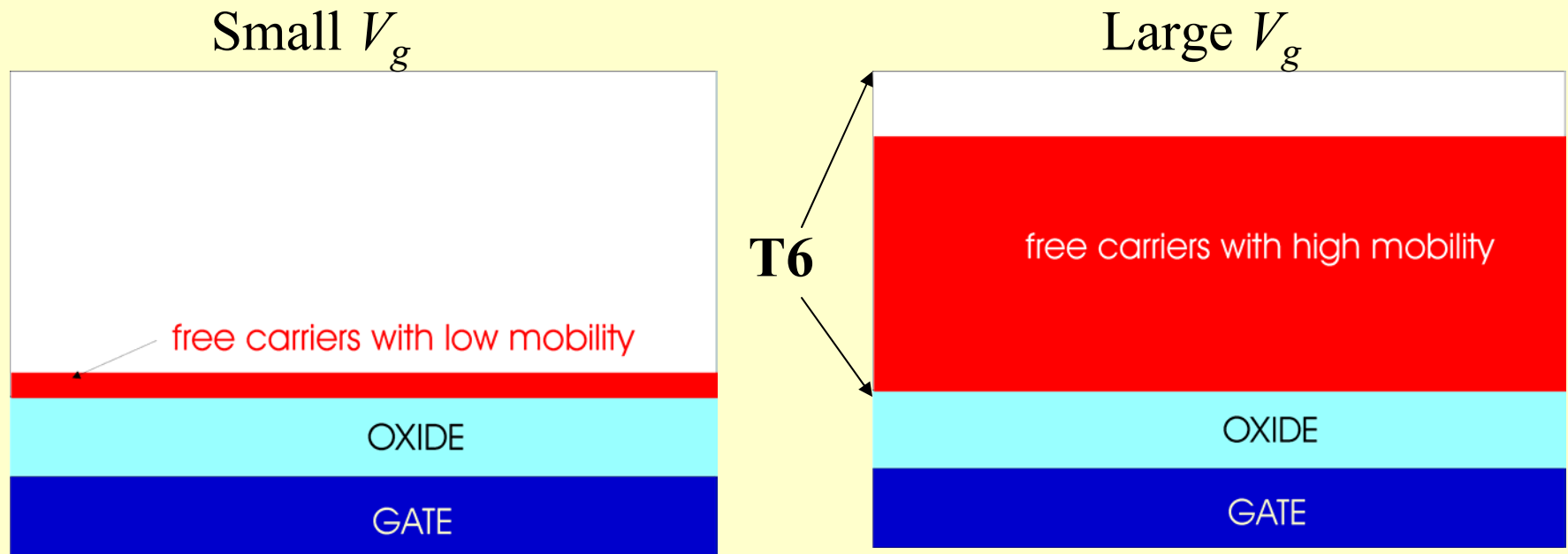
3 times better FETs

How to explain this?!



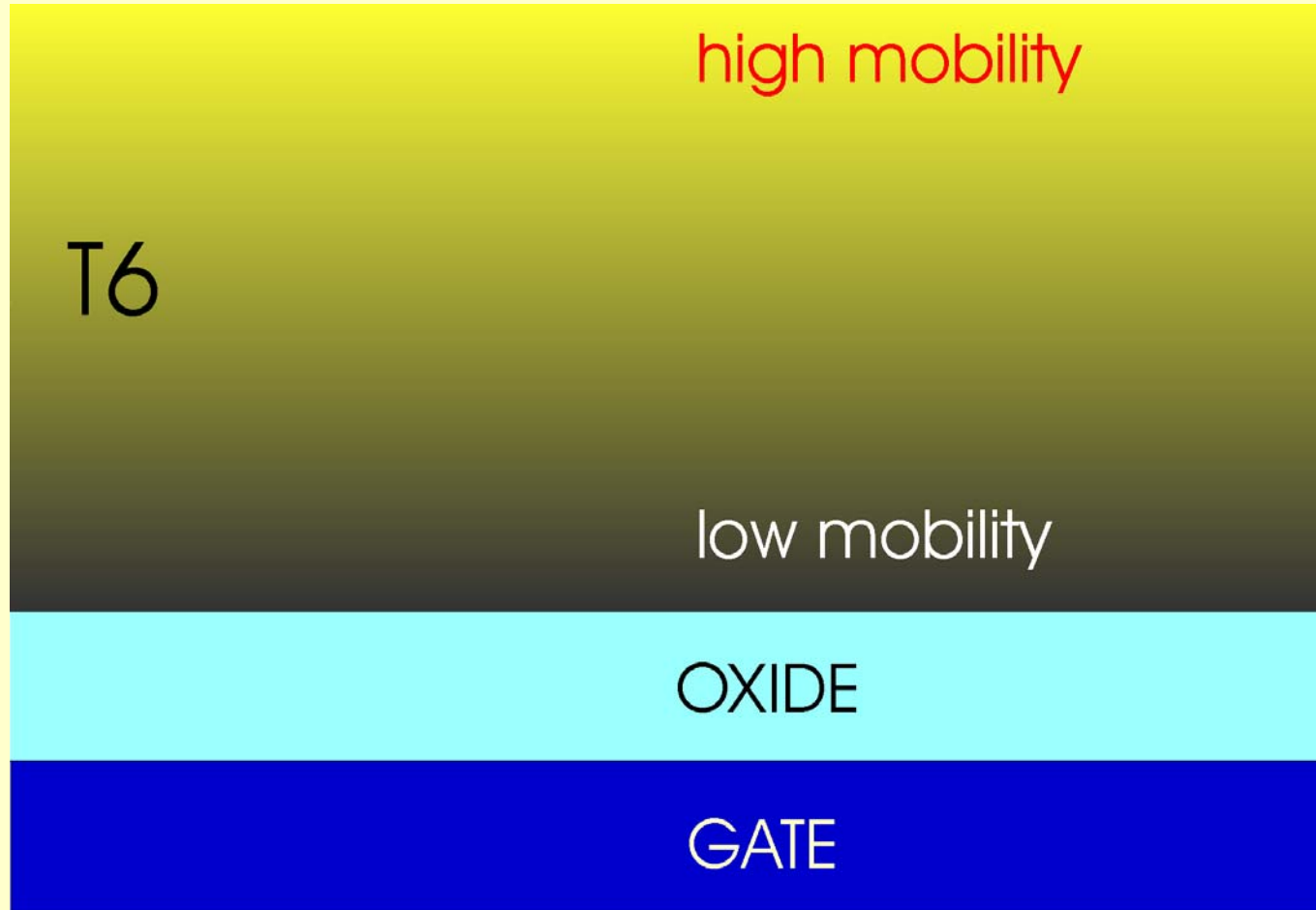
Field dependence

Experimental: Mobility increases with transverse electric field





Device cross section



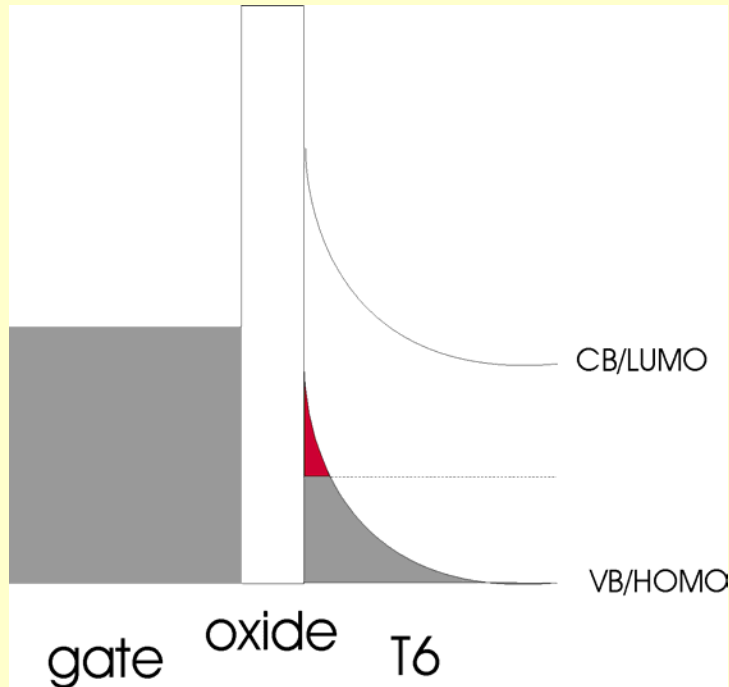
Highly ordered
(crystalline material
at surface

Messy layer at
interface

Mobility thus depends on film thickness

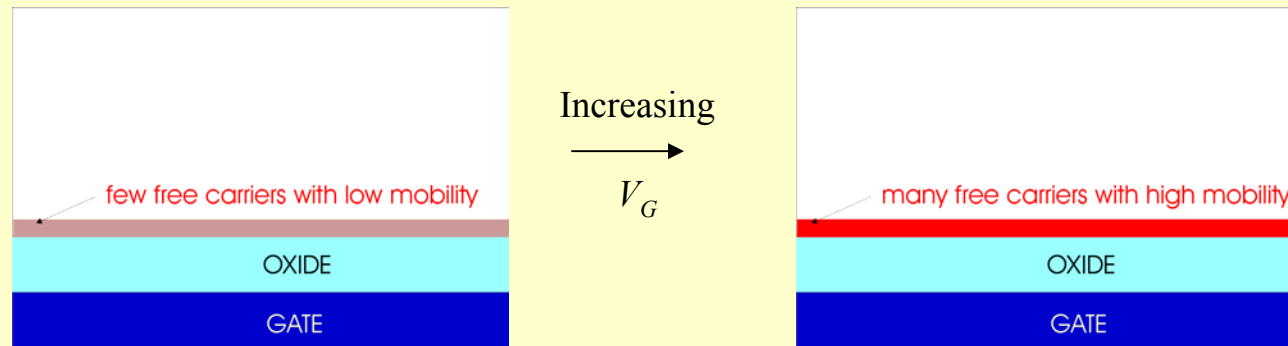


Device cross section



Mobility is of the first layer(s) and does NOT depend on film thickness

Increased V_G probes deeper VB states (with higher μ_p ?)





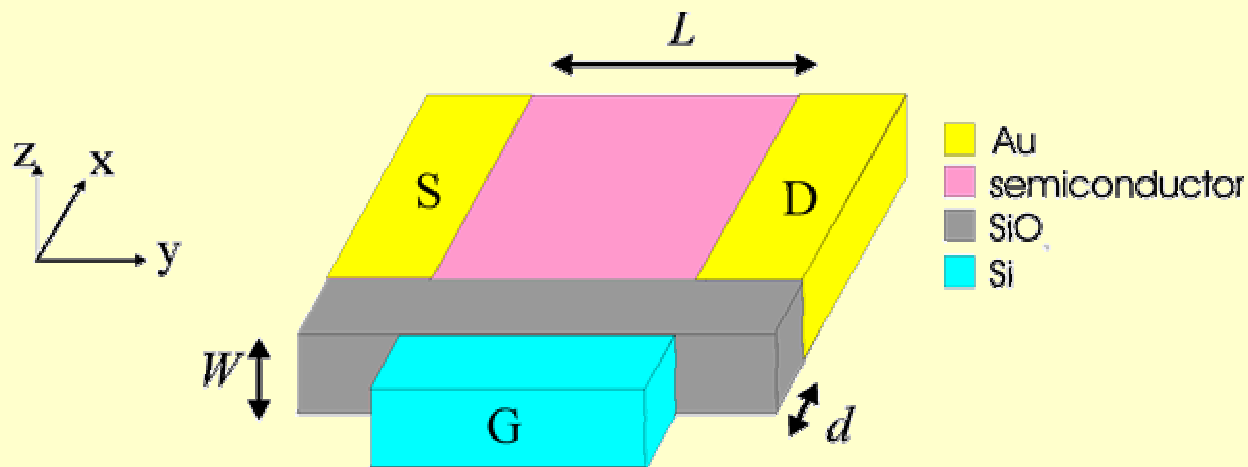
Effects of scaling down

For short channels the depletion width at the source and drain become relatively large.

The assumption $E_x \gg E_y$ is no longer valid

Effects:

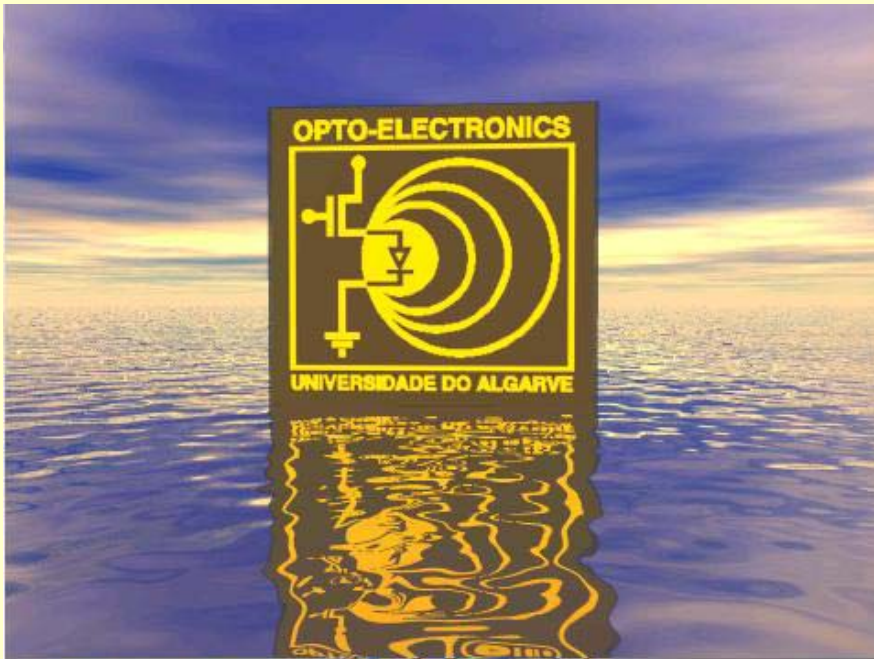
- Degradation of sub-threshold region ($V_{DS} < V_T$)
- V_T depending on L and V_{DS}
- No saturation





Summary

- V_T depends on V_{DS} . “Doping” inhomogeneity?
- 6th power law transfer curves.
- possibly due to μ_p depending on V_g due to film properties.
- No short channel effects seen yet.



Faro, June 2001